Serial No. 1862						SHEE	.101_		<u> </u>
Date Name Class Subclass Filing Date Appropriate	(REV. 7/80)				cet No. 1952		RECO	Serial No. 10/008,80	
Date Name Class Subclass Filing Date Appropriate	O / Bakor RE	EFERENC Several s	CES CITED BY APPLICANT sheets if necessary)			GA	18 81	un.	
Date Name Class Subclass Filing Date Appropriate	an 14 2023 8	الم		Applicant	: Shi et. al.	7	10 003	*	
Date Name Class Subclass Filing Date Appropriate	JUL ,	1			e: November 13, 200	1	7700	Group 17	61
Date Name Class Subclass Filing Date Appropriate	TRADOUT		U.S.	PATENT DOCU	MENTS			<u>-</u>	
AB US 4,977,252 12/1950 Chitu, Chung-Wai 536 102 08/1988 AC US 5,254,353 10/1993 Huang et al. 426 94 05/1992 AD US 5,559,463 10/1996 Timonen et al. 426 658 06/1994 AB US 5,559,469 02/1997 Chitu et al. 426 48 03/1996 AF COUNTY Class Subclass Translation AA AA AA AA AA EP 0242 913 10/1987 Europe C12P 19/72 X AM EP 0480 433 A2 04/1992 Europe A231 1/325 X AN WO 97/00620 01/1997 PGT -V-/ FD A23G 3/30 X AD JP 57144948 09/1982 Japan A231 1/00 Abstract OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) EXAMINER: Initial if reference considered, whether or not citation is in conformance with MBEP 666. Page 1/16 and the page of the page			Document Number	Date			Į.	Filing D	ro-
AC	NB	^_ /	US 4,762,721	08/1988	Holscher et al.	426	94	05/1986	
AD US 6,569,483 10/1996 Timonen et al. 426 658 06/1994 AE US 5,599,669 02/1997 Chiu et al. 426 48 03/1995 AF AG AG AH AH AI		AB '	US 4,977,252	12/1990	Chiu, Chung-Wai	536	102	08/1988	
AE US 5,599,569 02/1997 Chiu et al. 426 48 03/1995 AF AG AG AH AH AI		-	US 5,254,353	10/1993	Huang et al.	426	94	05/1992	_
AF	<u> </u>			10/1996	Timonen et al.	426	658	06/1994	
AH AH AI AJ AK FOREIGN PATENT DOCUMENTS FOREIGN PATENT DOCUMENTS Document Number Date Country Class Subclass Transiation Yes No NO AL EP 0 242 913 10/1987 Europe C12P 18/72 X AM EP 0 480 433 A2 04/1992 Europe A23L AN WO 97/00620 O1/1997 PCT-Wi i'd) A23G 330 X AO JP 57144948 09/1982 Japan A23L 1/00 Abstract OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR AS AT EXAMINER: Initial if reference considered, whether or not citation is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600. Days like the station is in conformance with MEE 600.	N3	+	US 5,599,569	02/1997	Chiu et al.	426	48	03/1995	
AH			+						
Al		+			<u></u>				
AJ		+		'	<u> </u>	1			
AK		+		'	<u> </u>				_
Document Number Date Country Class Subclass Translation		 		'		<u> </u>			
Document Number Date Country Class Subclass Translation	 	AK			<u></u>				
Document Number Date Country Class Subclass tion			FOREIG	IN PATENT DOC	UMENTS				
AL EP 0 242 913 AM EP 0 480 433 A2 O4/1992 Europe A23L 1/325 X AN WO 97/00620 O1/1997 PCT W; r A23G 3/30 X AO JP 57144948 O9/1982 Japan A23L 1/00 Abstract AP JP 57166943 OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR AS AT EXAMINER DATE CONSIDERED 12/3/03 TEXAMINER: Initial if reference considered, whether or not citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the part of the citation is in conformance with MPER 600. Pertiling the citation is in conformance with MPER 600. Pertiling the citation is in conformance with MPER 600. Pertiling the citation is in conformance with MPER 600. Pertiling the citation is in conformance with MPER 600. Pertiling the citation is in conformance with MPER 600. Pertiling the citation is in conformance with MPER 600. Pertiling the citation is in conformance with MPER 600. Pertiling the citation is in			Document Number	Date	te Country		Subclass		
AM EP 0 480 433 A2 04/1992 Europe A23L 1/325 X AN WO 97/00620 01/1997 PGT V/ i V A23G 3/30 X AO JP 57144948 09/1982 Japan A23L 1/00 Abstract AP JP 57166943 10/1982 Japan A23L 1/00 Abstract OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR AS AT DATE CONSIDERED 12/3/03 EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPER 600. Providing the abstract of the citation is in conformance with MPER 600. Providing the abstract of the citation is in conformance with MPER 600. Providing the abstract of the citation is in conformance with MPER 600. Providing the abstract of the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the abstract of the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in conformance with MPER 600. Providing the citation is in citation in citation in citation in citation is in citation in ci	10	+	=		 '	<u> </u>		Yes	No
AN WO 97/00620 O1/1997 PGT W, FU A23G 3/30 X AO JP 57144948 O9/1982 Japan A23L 1/00 Abstract OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR AS AS EXAMINER DATE CONSIDERED 12/3/03 EXAMINER: Initial if reference considered, whether or not citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in conformance with MEE See: Deput line through a citation is in citation i	1 N'5	++			 			 	
AO JP 57144948 09/1982 Japan A23L 1/00 Abstract AP JP 57166943 10/1982 Japan A23L 1/00 Abstract OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR AS AT EXAMINER BLut DATE CONSIDERED 12/3/03 EXAMINER: initial if reference considered, whether or not citation is in conformance with MEE See: Drove like the whole in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the whole interest in the conformance with MEE See: Drove like the c					 	 		 	
AP JP 57166943 10/1982 Japan A23L 1/00 Abstract OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR AS AS AT EXAMINER DATE CONSIDERED 12/3/03 *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MEE 608: Deput line through sites and the second sites of the		++				1		 	1_
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR AS AT EXAMINER DATE CONSIDERED 12/3/03 EXAMINER: initial if reference considered, whether or not citation is in conformance with MEE soe: Deput line through sites and the second se	112	++				1 1	 	1	
EXAMINER DATE CONSIDERED 12/3/03 EXAMINER: initial if reference considered, whether or not citation is in conformance with MEE see: Deput line through sites of the second seco	_~~_	171					1/00	Abstract	
EXAMINER DATE CONSIDERED 12/3/03 EXAMINER: Initial if reference considered, whether or not citation is in conformance with MEE see: Drove like through sites at the second seco		AR		Jing Audio,), Date, Peruncia ray	jes, Etc.,			
EXAMINER DATE CONSIDERED 12/3/03 *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with MEE soe: Deput line through sites in the conformance with the confor		+							
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPED size. Drove line through size in the conformance with MPED size.		+							
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPER size. Draw line through size is	EXAMINER	C	Shut	DATE CON	ISIDERED 12/3	7/03			
	*EXAMINER:	initial if	reference considered, whether or not mance and not considered. Include co	ot citation is in co	onformance with MPI	PED 600: D	Jenus line theresal	h citation if	not in

.#2

SHEET OF Form PTO-1449 U.S. Department of Commerce Atty. Docket No. 1952 Serial No. (REV. 7/80) Patent and Trademark Office LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary) Applicant: Chiu, et. al. Filing Date: November 12, 2001 Group **U.S. PATENT DOCUMENTS** *Examiner Initial **Document Number** Date Name Class Subclass Filing Date if Аррго-Priate AA US 5,756,140 05/26/98 Shoop, et. al. 426' 302 04/21/97 AB US 5,965,180 10/12/99 Lonergan, D 426 94 01/10/97 AC US 4,645,674 02/24/87 Lang, et. al. 426 94 07/06/84 AD US 5,599,569 02/04/97 Chiu, et. al. 426 48 03/28/95 AE AF AG AH ΑJ AK **FOREIGN PATENT DOCUMENTS** Transla-**Document Number** Date Country Class **Subclass** tion Yes No AL AM AN AO ΑP OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) AR Red Arrow Products Company LLC, "Tru Gold™", 633 South 20th Street, Manitowoc, WI 54220-1537 AS Par-Way Tryson Company, "Bake-Sheen", 107 Bolte Lane, St. Clair, Mo 63077 AT Par-Way Tryson Companies, The Makers of "Vegelene", 107 Bolte Lane, St. Clair, Mo 63077

*EXAMINER:

Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

DATE CONSIDERED